

1.	Record Nr.	UNINA9910481770003321
	Autore	Anon
	Titolo	Die psalmen des konincklicken Propheten Davids ende ander lofghesangen, wt den Francoysen dichte ghemaect door Clement Marot ende Theodore De Bese in Nederlandtsche spraecke overgheset door Petrus Dathenus [[electronic resource]]
	Pubbl/distr/stampa	London, : Merten Wendelen, 1566
	Descrizione fisica	Online resource (8°)
	Lingua di pubblicazione	Olandese
	Formato	Materiale a stampa
	Livello bibliografico	Monografia
	Note generali	Reproduction of original in Koninklijke Bibliotheek, Nationale bibliotheek van Nederland.
2.	Record Nr.	UNINA9910830071403321
	Autore	Molleman Areles
	Titolo	Patch clamping [[electronic resource] ] : an introductory guide to patch clamp electrophysiology / / Areles Molleman
	Pubbl/distr/stampa	New York, : J. Wiley, c2003
	ISBN	1-280-27051-9 9786610270514 0-470-85651-3 0-470-85652-1
	Descrizione fisica	1 online resource (187 p.)
	Disciplina	571.64 572/.437
	Soggetti	Patch-clamp techniques (Electrophysiology)
	Lingua di pubblicazione	Inglese
	Formato	Materiale a stampa
	Livello bibliografico	Monografia
	Note generali	Description based upon print version of record.
	Nota di bibliografia	Includes bibliographical references and index.

Patch Clamping; Contents; Preface; 1 Introduction; 1.1 Patch Clamping and its Context; 2 Basic Theoretical Principles; 2.1 Introduction to Membrane Biology; 2.1.1 The plasma membrane and its ionic environment; 2.1.2 Electrochemical gradients and the Nernst equation; 2.1.3 Maintenance of ion gradients and the membrane potential; 2.1.4 Ion channels; 2.2 Electrical Properties of the Cell Membrane; 2.2.1 Driving force and membrane resistance; 2.2.2 Membrane capacitance; 2.2.3 Consequences of membrane capacitance; 2.2.4 An electronic model of the plasma membrane  
2.3 Recording Modes and their Equivalent Circuits 2.3.1 The basics of equivalent circuits; 2.3.2 Intracellular recording; 2.3.3 Voltage clamp and current clamp; 2.3.4 Introduction to patch clamp configurations; 2.3.5 The equivalent circuit for the cell-attached patch configuration; 2.3.6 The equivalent circuit for the whole-cell configuration; 2.3.7 The equivalent circuit for the excised patch configurations; 3 Requirements; 3.1 The Platform; 3.1.1 Stability: vibrations and drift; 3.1.2 Where in the building should the set-up be placed?; 3.1.3 Anti-vibration tables; 3.2 Mechanics and Optics  
3.2.1 The microscope 3.2.2 Micromanipulators; 3.2.3 Pipette pressure; 3.2.4 Baths and superfusion systems; 3.3 Electrodes and Micropipettes; 3.3.1 Solid-liquid junction potentials and polarisation; 3.3.2 The bath electrode; 3.3.3 Micropipettes; 3.3.4 Liquid junction potentials; 3.4 Electronics; 3.4.1 External noise and Faraday cages; 3.4.2 Patch clamp amplifiers; 3.4.3 Noise prevention and signal conditioning; 3.4.4 Data acquisition and digitisation; 3.4.5 Computers and software; 4 The Practice of Patch Clamping; 4.1 Preparing the Experiment and Making a Seal; 4.1.1 Setting up  
4.1.2 Bringing the pipette near the preparation 4.1.3 Making the seal; 4.2 Whole-cell Modes; 4.2.1 Conventional whole-cell recording; 4.2.2 Perforated patch recording; 4.3 Single-channel Modes; 4.3.1 General notes; 4.3.2 Cell-attached patch; 4.3.3 Excised patches; 5 Whole-cell Protocols and Data Analysis; 5.1 Standard Cellular Parameters; 5.2 Voltage-activated Currents; 5.2.1 Introduction to pulse protocols; 5.2.2 Signal conditioning and positive/negative subtraction; 5.2.3 Space clamp artefacts; 5.2.4 Isolation of a homogeneous population of channels  
5.2.5 Current-voltage relationships and reversal potential 5.2.6 Determination of relative permeabilities; 5.2.7 Activation and inactivation studies; 5.3 Non-voltage-activated Currents; 5.3.1 Introduction to continuous recording; 5.3.2 Determination of reversal potential using voltage ramps; 6 Single-channel Protocols and Data Analysis; 6.1 General Single-channel Practice and Analysis; 6.1.1 Practical notes; 6.1.2 Amplitude analysis; 6.1.3 Event detection; 6.1.4 Dwell time analysis; 6.2 Continuous Recording of Single Channels; 6.2.1 Data acquisition; 6.2.2 Spontaneous activity  
6.2.3 Receptor-induced activity

Patch clamping is a widely applied electrophysiological technique for the study of ion channels; membrane proteins that regulate the flow of ions across cellular membranes and therefore influence the physiology of all cells. Patch Clamping aims to cover the basic principles and practical applications of this important technique. Starting with a review of the history of patch clamping, the text then goes on to cover the basic principles, platforms, equipment and environmental control, and will also include coverage of preparation types, recording modes and analysis of results. <

3. Record Nr.	UNINA9910960068603321
Titolo	Advanced reliability modeling : proceedings of the 2004 Asian International Workshop (AIWARM 2004) : Hiroshima, Japan, 26-27 August 2004 / / edited by Tadashi Dohi, Won Young Yun
Pubbl/distr/stampa	New Jersey ; ; London, : World Scientific, c2004
ISBN	9786611898717 9781281898715 1281898716 9789812702685 9812702687
Edizione	[1st ed.]
Descrizione fisica	1 online resource (645 p.)
Altri autori (Persone)	DohiTadashi YunWon Young
Disciplina	620.00452
Soggetti	Reliability (Engineering) - Mathematical models Computer networks - Reliability
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and author index.
Nota di contenuto	Preface T. Dohi and W. Y. Yun; Contents; Genetic Search for Redundancy Optimization in Complex Systems M. Agarwal and R. Gupta; Upper and Lower Bounds for 3-dimensional &within-consecutive- (r1 ,r2,r3)-out-of- (n1,n2 ,n3) : F System T. Akiba and H. Yamamoto; How Can We Estimate Software Reliability with a Continuous-state Software Reliability Model? T. Ando and T. Dohi; A Study on Reliable Multicast Applying Convolutional Codes over Finite Field M. Arai, S. Fukumoto and K. Iwasaki; Reliability Design of Industrial Plants using Petri Nets M. Bertolini, M. Bevilacqua and G. Mason Optimal Burn-in Procedures in a Generalized Environment J . H. Cha and J. MiPerforming the Soft-error Rate (SER) on a TDBI Chamber V. Chang and W. T. K. Chien; Enhancement of Reliability and Economy of a Thermal Power Generating System Through Prediction of Plant Efficiency Parameters A . Chatterjee, S. Chatterjee and I. Mukhopadhyay; Optimal Burn-in Time for General Repairable Products

Sold Under Warranties Y. H. Chien and S. H. Sheu  
 Determining Optimal Warranty Periods from the Seller's Perspective and Optimal Out-of-warranty Replacement Age from the Buyer's Perspective Y. H. Chien, S. H. Sheu and J. A. Chen  
 Warranty and Imperfect Repairs S. Chukova and Y. Hayakawa; Acceptance Sampling Plans Based on Failure-censored Step-stress Accelerated Tests for Weibull Distributions S. W. Chung, Y. S. Seo and W. Y. Yun; Availability for a Repairable System with Finite Repairs L. Cui and J. Li; A New Approach for the Fuzzy Reliability Analysis in Case of Discrete Fuzzy Variable Y. Dong, Z. Ni and C. Wang  
 Fuzzy Reliability Analysis of Complex Mechanical System Y. Dong, Z. Ni and C. Wang  
 Optimal Release Problem Based on the Number of Debuggings with Software Safety Model T. Fujiyoshi, K. Tokuno and S. Yamada; Operating Environment Based Maintenance and Spare Parts Planning: A Case Study B. Ghodrati and U. Kumar; Discrete-time Spare Ordering Policy with Lead Time and Discounting B. C. Giri, T. Dohi and N. Kaio; SNEM: A New Approach to Evaluate Terminal Pair Reliability of Communication Networks N. K. Goyal, R. B. Misra and S. K. Chaturvedi  
 Robust Design for Quality-reliability via Fuzzy Probability H. Guo  
 Interval-valued Fuzzy Set Modelling of System Reliability R. Guo; Fuzzy Set-valued Statistical Inferences on a System Operating Data R. Guo and E. Love; A Software Reliability Allocation Model Based on Cost-controlling C. Huang, R. Z. Xu and L. P. Zhang; Reliability of a Server System with Access Restriction M. Imaizumi, M. Kimura and K. Yasui; Continuous-state Software Reliability Growth Modeling with Testing-effort and Its Goodness-of-fit S. Inoue and S. Yamada  
 Analysis of Discrete-time Software Cost Model Based on NPV Approach K. Iwamoto, T. Dohi and N. Kaio

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## Sommario/riassunto

The 2004 Asian International Workshop on Advanced Reliability Modeling is a symposium for the dissemination of state-of-the-art research and the presentation of practice in reliability engineering and related issues in Asia. It brings together researchers, scientists and practitioners from Asian countries to discuss the state of research and practice in dealing with reliability issues at the system design (modeling) level, and to jointly formulate an agenda for future research in this engineering area. The proceedings cover all the key topics in reliability, maintainability and safety engineer

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